

Notice of References Cited	Application/Control No. 10/780,774	Applicant(s)/Patent Under Reexamination SHIRAKAWA ET AL.	
	Examiner Tu M. Nguyen	Art Unit 3748	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,763,656	07-2004	Bidner et al.	60/285
*	C	US-6,477,832	11-2002	Surnilla et al.	60/285
*	D	US-6,418,711	07-2002	Surnilla et al.	60/277
*	E	US-6,467,256	10-2002	Hashimoto, Akira	60/277
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*	G	US-6,698,187	03-2004	Nishioka et al.	60/277
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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